IEEE SCC20 16-1 Meeting
North Reading, Massachusetts
Opening Plenary

1) CALL TO ORDER (*Mike Seavey*)

Meeting called to order at 9:12 AM

2) ANOUNCEMENTS *(Teresa Lopes)*

3) INTRODUCTIONS/ATTENDANCE SHEET (*All*)

4) CALL FOR PATENTS (*Mike Seavey*)

See IEEE Patent Slides

5) 16-1 MEETING AGENDA (*Mike Seavey*)

Updated agenda reviewed

6) CHAIRS REPORT & SCC20's 50TH ANIVERSARY (*Mike Seavey*)

See SCC20 16-1 Chairs Report

7) NEW SCC20 COMMITTEE & WORKING GROUP WEB PAGES (*Christy Bahn*)

Christy Bahn showed the group a preview of the new committee and working group pages. There was a lot of discussion about what to do with the old sub-committee pages. We want to keep the old sub-committee data around. There are external links to these pages that we would like not to break.
Additional feedback should be sent to Christy Bahn.

8) WORKING GROUP PLANS FOR THIS MEETING

P1445 WG– *M. Seavey*

Review final document. The Document basically done. Going to Steering to start Sponsor ballot

P1505.1 WG– *S. Mann / R. Spinner*

Review and mark up current standard. Would like a Word version of the standard from the IEEE.

P1514 WG– *S. Mann / R. Spinner*

Review components and get into the details – still a lot of work to be done

P1636 WG– *M. Seavey / J. Sheppard*

Update the previously published standard to latest template. Roll SIMICA common into the base standard. EXPRESS has been dropped. Replacing with OWL (stronger compatibility with XML).

P1636.2 WG– *M. Seavey / J. Sheppard*

Review candidate OWL ontology. Will eventually do the same thing for 1636.1

P1641.1a WG– C*. Gorringe / I. Neag*

Adding amendment for TSF libraries (guidance). Review work being done with digital buses. eCASS suite of TSF libraries to represent the ATLAS.

P1671.1 WG– *A. Jain*

Finalizing schema for new data flows. Review schema and examples. Finished schema for digital and serial buses. Hope to close 9 of the 11 remaining open issues. Publish schema to box.net in September

P1671.3 WG– *I. Neag*

One open action item. Will get closed once serial bus issues with 1671.1 get closed

P1871.2 WG– *C. Gorringe / T. Winquist*

Review document and get ready to go to ballot. All feedback has been incorporated

9) STUDY GROUP PLANS FOR THIS MEETING

1505 – S. *Mann*

Looking for feedback to figure out what to do with the standard

10) IEC TC91 WG 15 REPORT *(Mike Seavey)*

On May 17, the TC91 chair (Chris Hunt (UK)) approved having Mike as acting convener of the WG15 meeting.

Meeting on Thursday

11) ADJOURN TO WORKING GROUPS

Instructions for the WG Chair

The IEEE-SA strongly recommends that at each WG meeting the chair or a designee:

- **Show slides #1 through #4 of this presentation**
- **Advise the WG attendees that:**
  - The IEEE's patent policy is described in Clause 6 of the *IEEE-SA Standards Board Bylaws*;
  - Early identification of patent claims which may be essential for the use of standards under development is strongly encouraged;
  - There may be Essential Patent Claims of which the IEEE is not aware. Additionally, neither the IEEE, the WG, nor the WG chair can ensure the accuracy or completeness of any assurance or whether any such assurance is, in fact, of a Patent Claim that is essential for the use of the standard under development.
- **Instruct the WG Secretary to record in the minutes of the relevant WG meeting:**
  - That the foregoing information was provided and that slides 1 through 4 (and this slide 0, if applicable) were shown;
  - That the chair or designee provided an opportunity for participants to identify patent claim(s)/patent application claim(s) and/or the holder of patent claim(s)/patent application claim(s) of which the participant is personally aware and that may be essential for the use of that standard
  - Any responses that were given, specifically the patent claim(s)/patent application claim(s) and/or the holder of the patent claim(s)/patent application claim(s) that were identified (if any) and by whom.
- The WG Chair shall ensure that a request is made to any identified holders of potential essential patent claim(s) to complete and submit a Letter of Assurance.
- It is recommended that the WG chair review the guidance in *IEEE-SA Standards Board Operations Manual* 6.3.5 and in FAQs 14 and 15 on inclusion of potential Essential Patent Claims by incorporation or by reference.

Note: **WG** includes Working Groups, Task Groups, and other standards-developing committees with a PAR approved by the IEEE-SA Standards Board.

(Optional to be shown)

Participants, Patents, and Duty to Inform

All participants in this meeting have certain obligations under the IEEE-SA Patent Policy.

- Participants [Note: Quoted text excerpted from IEEE-SA Standards Board Bylaws subclause 6.2]:
  - “Shall inform the IEEE (or cause the IEEE to be informed)” of the identity of each “holder of any potential Essential Patent Claims of which they are personally aware” if the claims are owned or controlled by the participant or the entity the participant is from, employed by, or otherwise represents
  - “Should inform the IEEE (or cause the IEEE to be informed)” of the identity of “any other holders of potential Essential Patent Claims” (that is, third parties that are not affiliated with the participant, with the participant’s employer, or with anyone else that the participant is from or otherwise represents)
- The above does not apply if the patent claim is already the subject of an Accepted Letter of Assurance that applies to the proposed standard(s) under consideration by this group
- Early identification of holders of potential Essential Patent Claims is strongly encouraged
- No duty to perform a patent search

Patent Related Links

All participants should be familiar with their obligations under the IEEE-SA Policies & Procedures for standards development.

Patent Policy is stated in these sources:

IEEE-SA Standards Boards Bylaws

http://standards.ieee.org/develop/policies/bylaws/sect6-7.html#6

IEEE-SA Standards Board Operations Manual

http://standards.ieee.org/develop/policies/opman/sect6.html#6.3

Material about the patent policy is available at

http://standards.ieee.org/about/sasb/patcom/materials.html

If you have questions, contact the IEEE-SA Standards Board Patent Committee Administrator at patcom@ieee.org or visit http://standards.ieee.org/about/sasb/patcom/index.html

This slide set is available at https://development.standards.ieee.org/myproject/Public/mytools/mob/slideset.ppt

Call for Potentially Essential Patents

- If anyone in this meeting is personally aware of the holder of any patent claims that are potentially essential to implementation of the proposed standard(s) under consideration by this group and that are not already the subject of an Accepted Letter of Assurance:
  - Either speak up now or
  - Provide the chair of this group with the identity of the holder(s) of any and all such claims as soon as possible or
  - Cause an LOA to be submitted

Other Guidelines for IEEE WG Meetings

- **All IEEE-SA standards meetings shall be conducted in compliance with all applicable laws, including antitrust and competition laws.**
  - **Don’t discuss the interpretation, validity, or essentiality of patents/patent claims.**
  - **Don’t discuss specific license rates, terms, or conditions.**
    - Relative costs, including licensing costs of essential patent claims, of different technical approaches may be discussed in standards development meetings.
      - Technical considerations remain primary focus
  - **Don’t discuss or engage in the fixing of product prices, allocation of customers, or division of sales markets.**
  - **Don’t discuss the status or substance of ongoing or threatened litigation.**
  - **Don’t be silent if inappropriate topics are discussed … do formally object.**

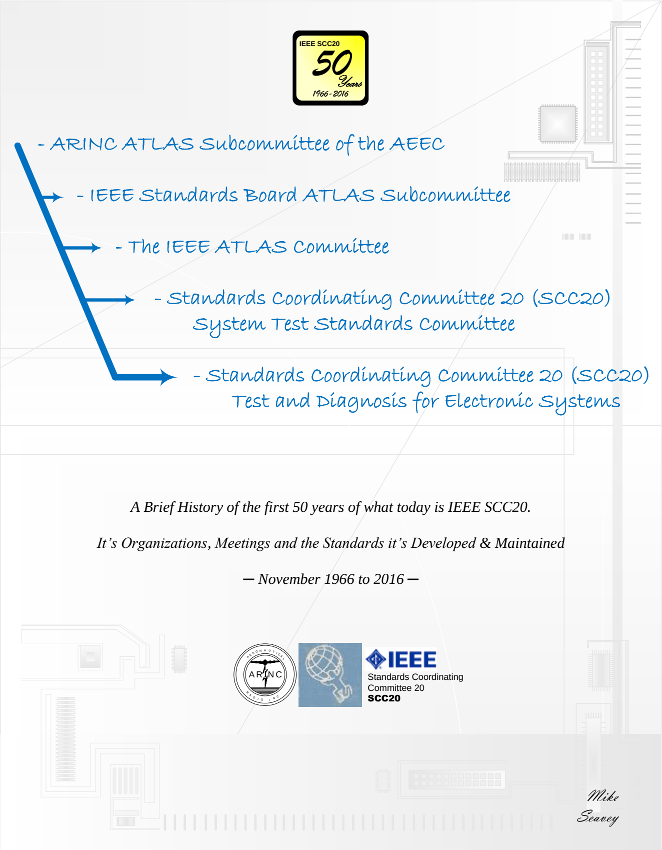
See *IEEE-SA Standards Board Operations Manual*, clause 5.3.10 and “Promoting Competition and Innovation: What You Need to Know about the IEEE Standards Association's Antitrust and Competition Policy” for more details.

Chairs Report

SCC20’s 50th Anniversary

1966-2016

- I have created a 25 page brief history of the Committee.
  - Beginnings, Meeting Locations/Dates, Standards Worked, Organizations, Time Line of Events, Group Photos, Various Logos, Document Covers.
  - PDF and Paper Copies available.
  - Available on the “new” SCC20 web-site.



IEEE SCC20 50 Years 1966-2016

- ARINC ATLAS Subcommittee of the AEEC
- IEEE Standards Board ATLAS Subcommittee
- The IEEE ATLAS Committee
- Standards Coordinating Committee 20 (SCC20) System Test Standards Committee
- Standards Coordinating Committee 20 (SCC20) Test and Diagnosis for Electronic Systems

A Brief History of the first 50 years of what today is IEEE SCC20.

It’s Organizations, Meetings and the Standards it’s Developed & Maintained

— November 1966 to 2016 —

ARINC IEEE Standards Coordinating Committee 20 SCC20

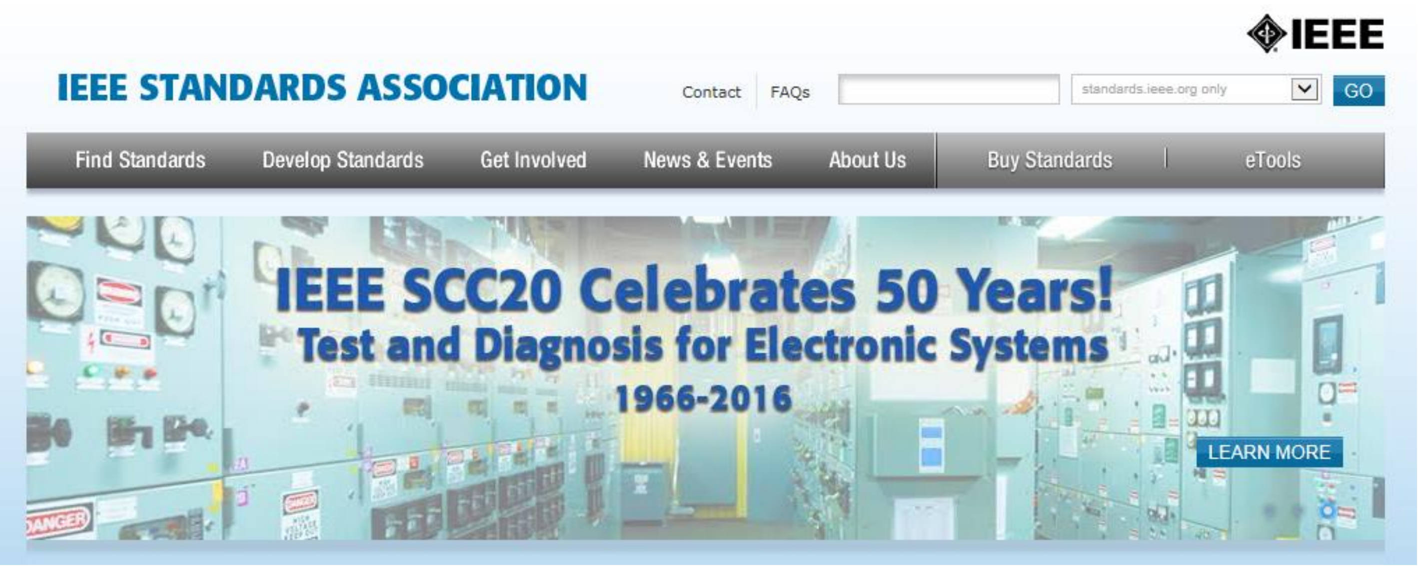
Mike Seavey

- Working with the IEEE, we have created a SCC20 Lapel Pin.

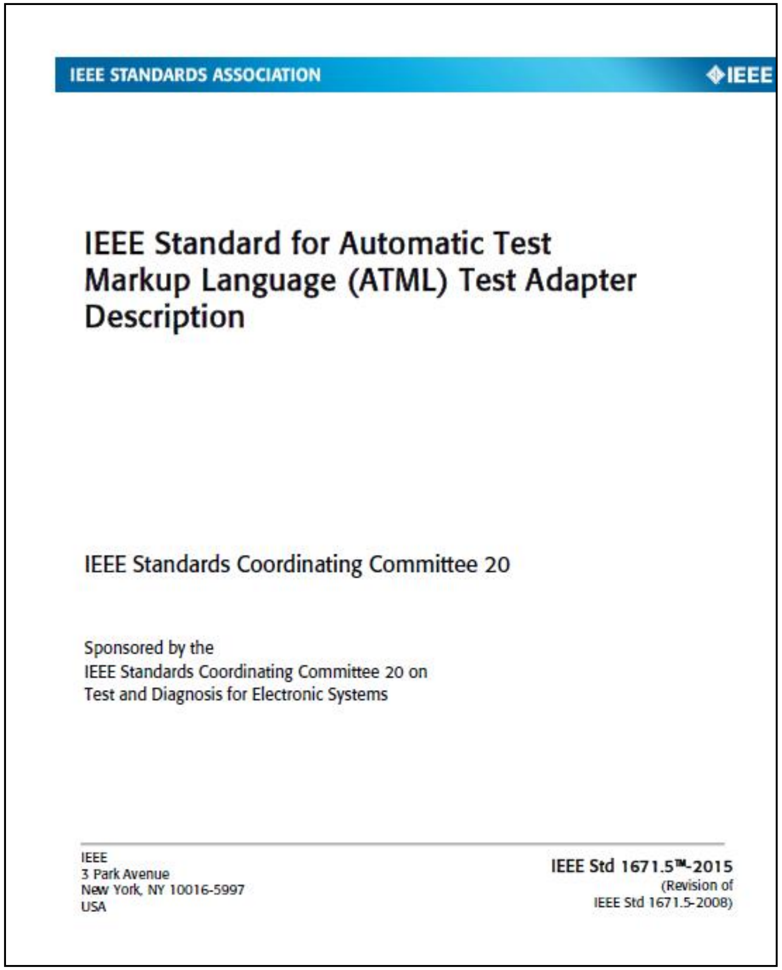
SCC20’s 50th Anniversary

1966-2016

- I was interviewed by the IEEE for:
  - The IEEE Standards Insight Blog. (available now)
  - The IEEE History Center Newsletter. (for the July publication)
    - The IEEE History Center is located at the Stevens Institute of Technology in Hoboken NJ.
  - IEEE-SA website - http://standards.ieee.org/



Working Group Chair Awards



IEEE STANDARDS ASSOCIATION

IEEE Standard for Automatic Test Markup Language (ATML) Test Adapter Description

IEEE Standards Coordinating Committee 20

Sponsored by the
IEEE Standards Coordinating Committee 20 on
Test and Diagnosis for Electronic Systems

IEEE
3 Park Avenue
New York, NY 10016-5997
USA

IEEE Std 1671.5™-2015
(Revision of
IEEE Std 1671.5-2008)

IEEE STANDARDS ASSOCIATION

IEEE Standard for Automatic Test Markup Language (ATML) Test Station Description

IEEE Standards Coordinating Committee 20

Sponsored by the
IEEE Standards Coordinating Committee 20 on
Test and Diagnosis for Electronic Systems

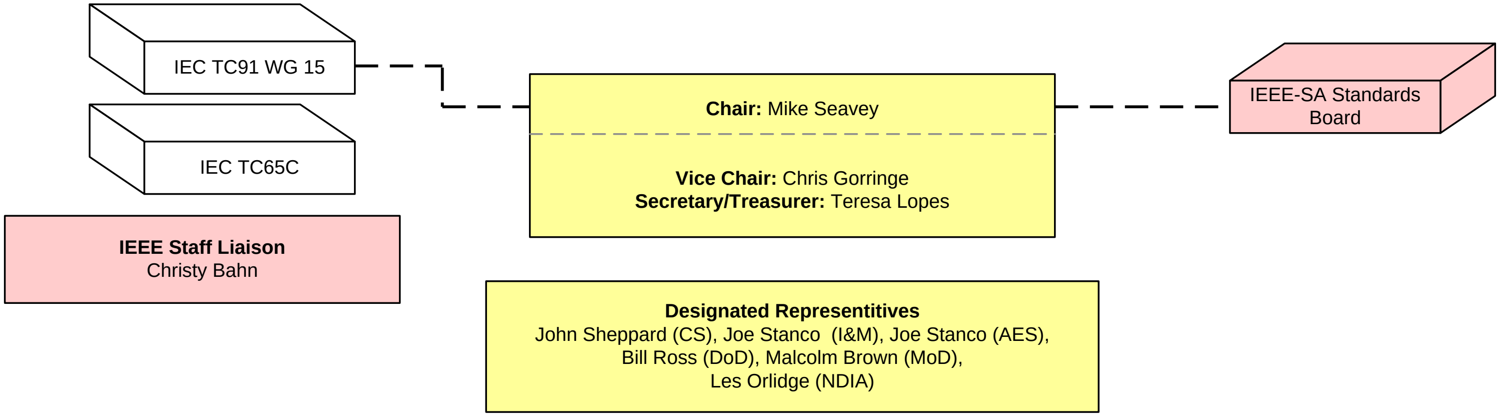
IEEE
3 Park Avenue
New York, NY 10016-5997
USA

IEEE Std 1671.6™-2015
(Revision of
IEEE Std 1671.6-2008)

Committee Introduction

- We are developing and/or maintaining a total of 30 active standards.
- We presently have 9 have active Project Authorization Requests (PAR)s.
- We operate under the IEEE Operating Hierarchy as well as:
  - Policies and Procedures for Standards Development for the Standards Coordinating Committee 20 (SCC20)
  - Policies and Procedures for: SCC20 Working Groups

SCC20 Organization



IEC TC91 WG 15

IEC TC65C

IEEE Staff Liaison
Christy Bahn

Chair: Mike Seavey

Vice Chair: Chris Gorringe
Secretary/Treasurer: Teresa Lopes

IEEE-SA Standards Board

Designated Representitives
John Sheppard (CS), Joe Stanco (I&M), Joe Stanco (AES),
Bill Ross (DoD), Malcolm Brown (MoD),
Les Orlidge (NDIA)

IEEE-P1445
DTIF
Revision of
IEEE-1445-1998 (R2010)
WG Chair: Mike Seavey

IEEE-P1636
SIMICA
Revision of
IEEE-1636-2009
WG Chair: John Sheppard

IEEE-P1671.1
ATML: Test Description
Revision of
IEEE-1671.1-2009
WG Chair: Anand Jain

IEEE-P1505.1
Common Test Interface Pin Map Configuration
Revision of
IEEE-1505.1-2008
WG Chair: Rob Spinner

IEEE-P1636.2
SIMICA: MAI
Revision of
IEEE-1636.2-2010
WG Chair: John Sheppard

IEEE-P1671.3
ATML: UUT Description
Revision of
IEEE-1671.1-2007
WG Chair: Ion Naeg

IEEE-P1514
Fixtures Applied to Generic Test Interfaces
New Recommended Practice
WG Chair: Steve Mann

IEEE-P1641.1a
Amendment to IEEE-1641.1
New Amendment
WG Chair: Ion Naeg

IEEE-P1871.2
Intrinsic Signal Path Information
New Recommended Practice
WG Chair: Chris Gorringe

Active Working Groups (Revision to a Published Standard or Development of the Initial Standard)

IEEE-448.1-2003
IEEE-448.2-1992
IEEE-716-1995 (R2011)
IEEE-771-1998 (R2009)
IEEE-1155-1992
IEEE-1174-2000
IEEE-1232-2010
IEEE-1232.3-2014
IEEE-1505-2010
IEEE-1505.3-2015
IEEE-1546-2000 (R2011)
IEEE-1636.1-2013
IEEE-1636.99-2013
IEEE-1641-2010
IEEE-1641.1-2013
IEEE-1671-2010
IEEE-1671.2-2012
IEEE-1671.4-2014
IEEE-1671.5-2015
IEEE-1671.6-2015
IEEE-1871.1-2014

Published IEEE Standards (Maintained By SCC20)

SCC20 Standards Tracking

Publication	Project	PAR by	PAR Approval Date	PAR Expiration Date	Valid Standard Until	IEC Adoption	
488.1-2003	—	2015	—	—	3/19/2019	IEC 60488-1 First Edition 2004-07	Standard approved by the SASB 6/12/2003, by ANSI 10/10/2003 Moved from TC8 Sept. 2015
488.2-1992	—	2016	—	—	6/17/2020	IEC 60488-2 First Edition 2004-05	Standard approved by the SASB 6/18/1992, by ANSI 1/4/1993 Moved from TC8 Sept. 2015
716-1995(R2011)	—	2017	—	—	12/31/2021	IEC 61926-1 Ed. 1.0	Administratively Withdraw in 2021
771-1998(R2009)	—	2015	—	—	12/9/2019		Administratively Withdraw in 2019
1155-1992	—	2014	—	—	12/31/2018	—	Moved from TC8 Sept. 2015
1174-2000	—	2015	—	—	3/19/2019	—	Moved from TC8 Sept. 2015
1232-2010	—	2016	—	—	12/8/2020	IEC 62243 Ed. 2.0	
1232.3-2014	—	2020	—	—	12/31/2024		
1445-1998(R2010)	P1445	—	September 3, 2015	December 31, 2019	12/8/2019	IEC 61445 Ed 1.0	Going into Sponsor Ballot in 2016
1505-2010	—	2016	—	—	9/30/2020	IEC 63004 Ed 1.0	IEC Published December 30, 2015
1505.1-2008	P1505.1	—	December 5, 2015	December 31, 2019	12/31/2018	IEC 63003 Ed 1.0	IEC Published December 30, 2015
1505.3-2015	—	2021	—	—	12/31/2025		
—	P1514		December 10, 2014	December 31, 2018	—		
1546-2000(R2011)	—	2017	—	—	12/31/2021		Merged material with 1445, Administratively Withdraw in 2021
1636-2009	P1636	—	December 5, 2015	December 31, 2019	12/31/2019		Under the IEC SMB question in principle vote for the dual logo process
1636.1-2013	—	2019	—	—	12/31/2023		Under the IEC SMB question in principle vote for the dual logo process
1636.2-2010	P1636.2	—	August 23, 2013	December 31, 2017	12/31/2020		
1636.99-2013	—	2019	—	—	12/31/2023		Under the IEC SMB question in principle vote for the dual logo process
1641-2010	—	2016	—	—	6/17/2020	IEC 62529 Ed. 2.0	
1641.1-2013	—	2019	—	—	12/31/2023		
—	P1641.1a	—	December 11, 2013	December 31, 2017	—		
1671-2010	—	2016	—	—	9/30/2020	IEC 61671 Ed 1.0	
1671.1-2009	P1671.1	—	June 17, 2010	December 31, 2016	12/31/2019		
1671.2-2012	—	2018	—	—	12/31/2022	IEC 61671-2 Ed 1.0	IEC Published April 8, 2016
1671.3-2007	P1671.3	—	June 17, 2010	December 31, 2016	12/31/2018		
1671.4-2014	—	2020	—	—	12/31/2024	IEC 61671-4 Ed 1.0	IEC Published April 8, 2016
1671.5-2015	—	2021	—	—	12/31/2025	IEC 61671-5 Ed 1.0	IEC Published April 8, 2016
1671.6-2015	—	2021	—	—	12/31/2025	IEC 61671-6 Ed 1.0	IEC Published April 8, 2016
1871.1-2014	—	—	—	—	12/31/2024		
—	P1871.2	—	June 16, 2011	December 31, 2017	—		
As of 5/19/2016		Discuss	In Publication	PAR due to expire	In ballot	IEC TC91 WG 15	Design Automation: Testing of Electrotechnical Products
		Std. inactive before the PAR expires				IEC TC65C	Industrial Networks

SASB Meeting Deadlines & Schedules 2016

Deadline for Submission	Meeting
December 9, 2015 √	January 19: NesCom/RevCom telecon √
January 22, 2016 √	**March 1-3: New Delhi India √**
March 22, 2016 √	May 2: NesCom/RevCom telecon √
May 20, 2016 √	**June 28-30: Berlin Germany**
August 5, 2016	September 16: NesCom/RevCom telecon
	September 22: SASB telecon
October 17, 2016	**December 5-7: Piscataway NJ**

√ = Meeting or deadline has occurred

SASB Meeting Deadlines & Schedules 2017

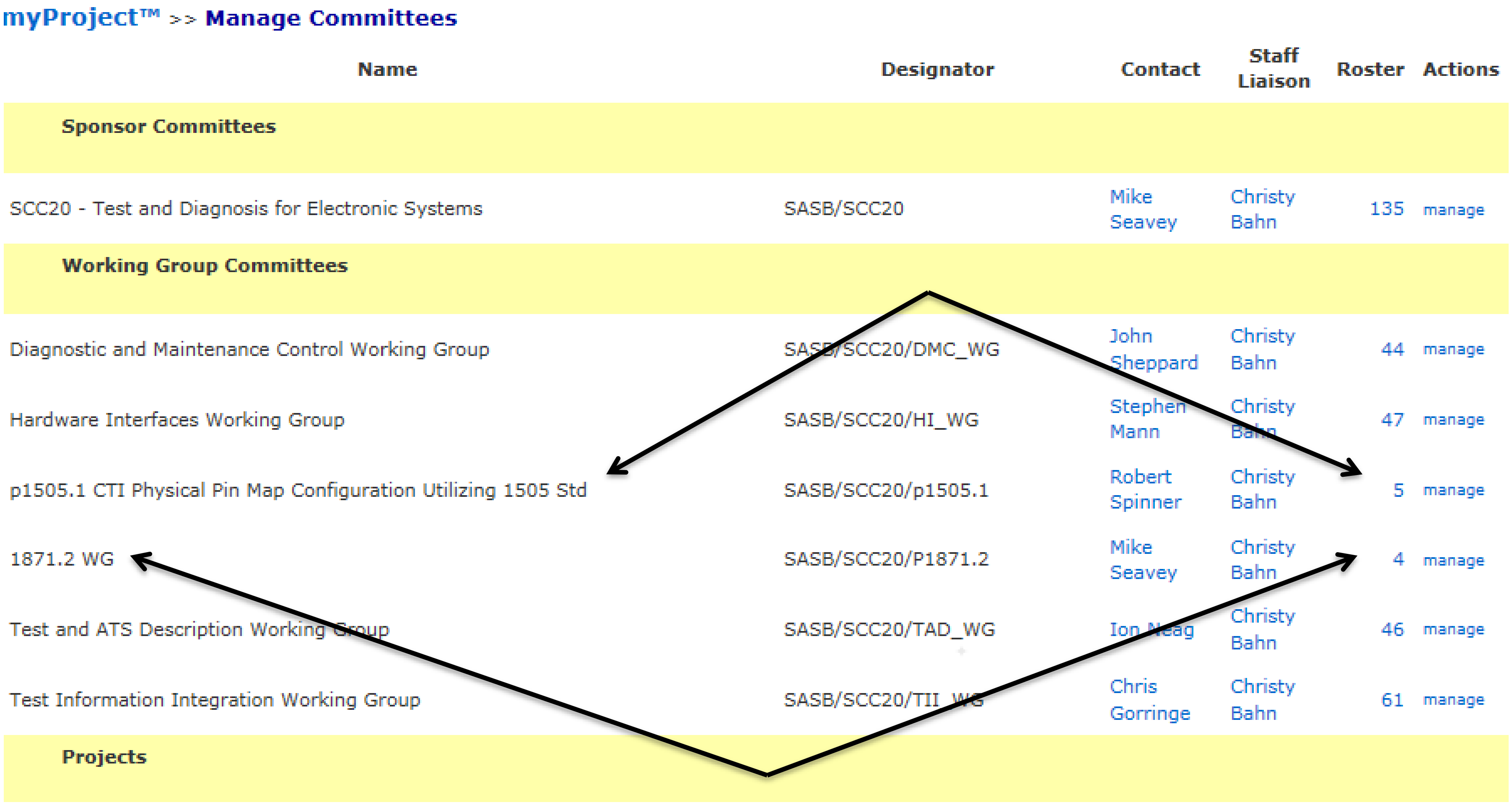
Deadline for Submission	Meeting
December 20, 2016	January 30: NesCom/RevCom telecon
February 10, 2017	**March 21-23: Shenzhen China**
March 24, 2017	May 4: NesCom/RevCom telecon
May 5, 2017	**June 13-15: Milan Italy**
July 28, 2017	September 7: NesCom/RevCom telecon
	September 28: SASB telecon
October 16, 2017	**December 4-6: Piscataway NJ**

Committee Quorum Numbers

- ***“Steering”*** **(12 voting members)**
  - 6

Mike Seavey, Chris Gorringe, Teresa Lopes, John Sheppard, Joe Stanco, Bill Ross, Malcolm Brown, Les Orlidge, Steve Mann, Rob Spinner, Ion Naeg, Anand Jain

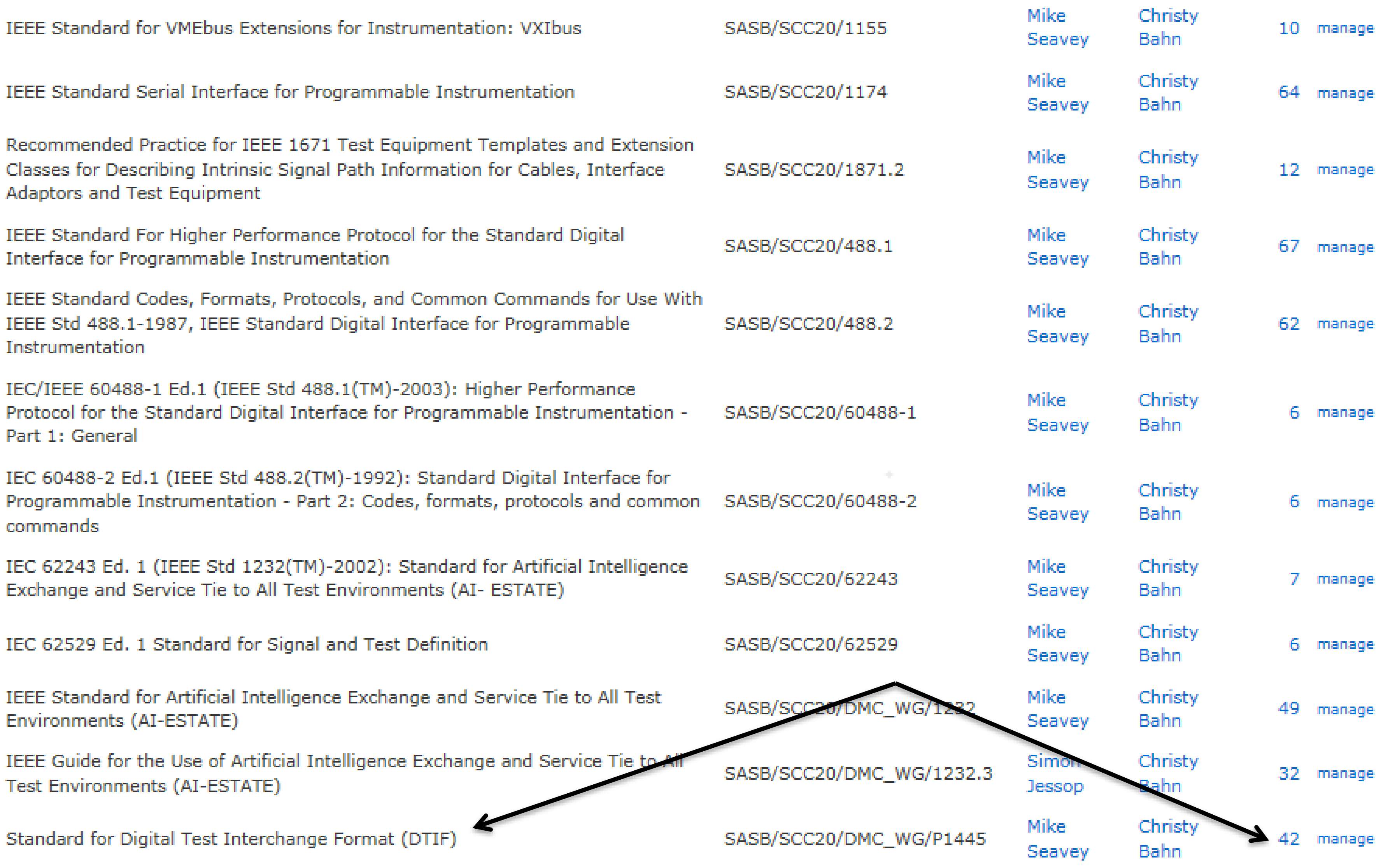
Working Group Quorum



myProject™ >> **Manage Committees**

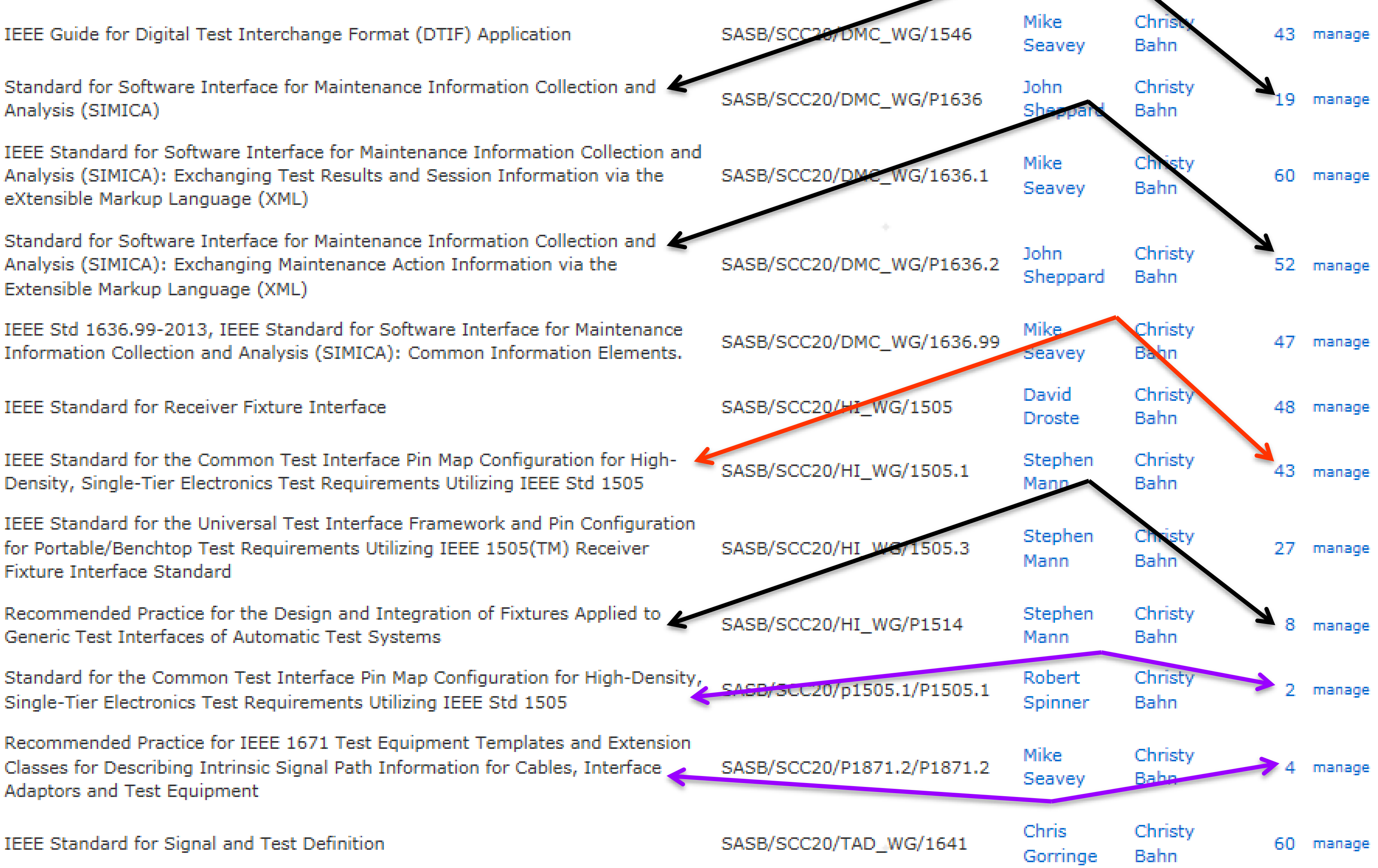
Name	Designator	Contact	Staff Liaison	Roster	Actions
Sponsor Committees					
SCC20 - Test and Diagnosis for Electronic Systems	SASB/SCC20	Mike Seavey	Christy Bahn	135	manage
Working Group Committees					
Diagnostic and Maintenance Control Working Group	SASB/SCC20/DMC_WG	John Sheppard	Christy Bahn	44	manage
Hardware Interfaces Working Group	SASB/SCC20/HI_WG	Stephen Mann	Christy Bahn	47	manage
p1505.1 CTI Physical Pin Map Configuration Utilizing 1505 Std	SASB/SCC20/p1505.1	Robert Spinner	Christy Bahn	5	manage
1871.2 WG	SASB/SCC20/P1871.2	Mike Seavey	Christy Bahn	4	manage
Test and ATS Description Working Group	SASB/SCC20/TAD_WG	Ion Neag	Christy Bahn	46	manage
Test Information Integration Working Group	SASB/SCC20/TII_WG	Chris Gorringe	Christy Bahn	61	manage
Projects					

Working Group Quorum



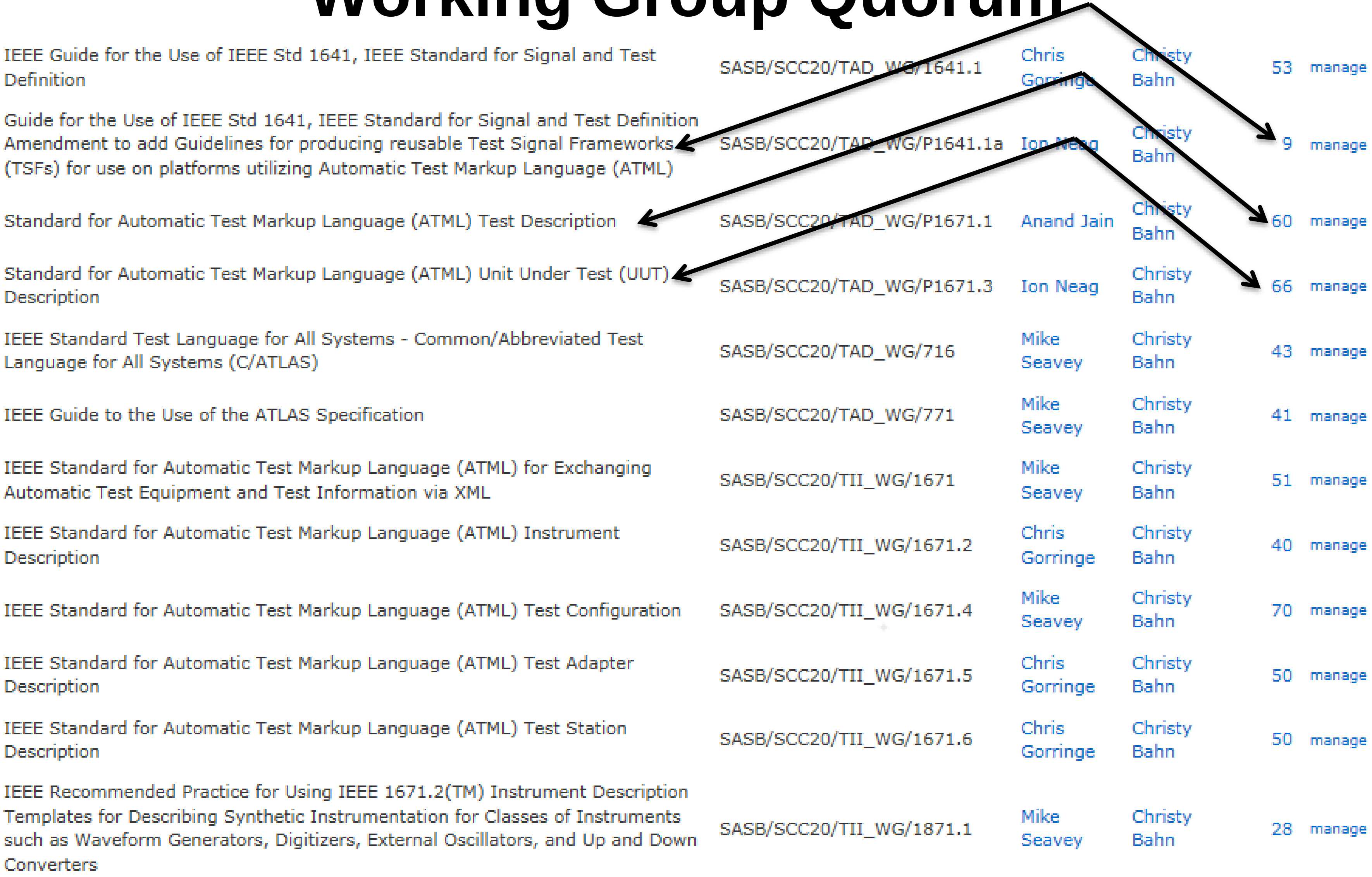
IEEE Standard for VMEbus Extensions for Instrumentation: VXIbus	SASB/SCC20/1155	Mike Seavey	Christy Bahn	10	manage
IEEE Standard Serial Interface for Programmable Instrumentation	SASB/SCC20/1174	Mike Seavey	Christy Bahn	64	manage
Recommended Practice for IEEE 1671 Test Equipment Templates and Extension Classes for Describing Intrinsic Signal Path Information for Cables, Interface Adaptors and Test Equipment	SASB/SCC20/1871.2	Mike Seavey	Christy Bahn	12	manage
IEEE Standard For Higher Performance Protocol for the Standard Digital Interface for Programmable Instrumentation	SASB/SCC20/488.1	Mike Seavey	Christy Bahn	67	manage
IEEE Standard Codes, Formats, Protocols, and Common Commands for Use With IEEE Std 488.1-1987, IEEE Standard Digital Interface for Programmable Instrumentation	SASB/SCC20/488.2	Mike Seavey	Christy Bahn	62	manage
IEC/IEEE 60488-1 Ed.1 (IEEE Std 488.1(TM)-2003): Higher Performance Protocol for the Standard Digital Interface for Programmable Instrumentation - Part 1: General	SASB/SCC20/60488-1	Mike Seavey	Christy Bahn	6	manage
IEC 60488-2 Ed.1 (IEEE Std 488.2(TM)-1992): Standard Digital Interface for Programmable Instrumentation - Part 2: Codes, formats, protocols and common commands	SASB/SCC20/60488-2	Mike Seavey	Christy Bahn	6	manage
IEC 62243 Ed. 1 (IEEE Std 1232(TM)-2002): Standard for Artificial Intelligence Exchange and Service Tie to All Test Environments (AI- ESTATE)	SASB/SCC20/62243	Mike Seavey	Christy Bahn	7	manage
IEC 62529 Ed. 1 Standard for Signal and Test Definition	SASB/SCC20/62529	Mike Seavey	Christy Bahn	6	manage
IEEE Standard for Artificial Intelligence Exchange and Service Tie to All Test Environments (AI-ESTATE)	SASB/SCC20/DMC_WG/1232	Mike Seavey	Christy Bahn	49	manage
IEEE Guide for the Use of Artificial Intelligence Exchange and Service Tie to All Test Environments (AI-ESTATE)	SASB/SCC20/DMC_WG/1232.3	Simon Jessop	Christy Bahn	32	manage
Standard for Digital Test Interchange Format (DTIF)	SASB/SCC20/DMC_WG/P1445	Mike Seavey	Christy Bahn	42	manage

Working Group Quorum



IEEE Guide for Digital Test Interchange Format (DTIF) Application	SASB/SCC20/DMC_WG/1546	Mike Seavey	Christy Bahn	43	manage
Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA)	SASB/SCC20/DMC_WG/P1636	John Sheppard	Christy Bahn	19	manage
IEEE Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA): Exchanging Test Results and Session Information via the eXtensible Markup Language (XML)	SASB/SCC20/DMC_WG/1636.1	Mike Seavey	Christy Bahn	60	manage
Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA): Exchanging Maintenance Action Information via the Extensible Markup Language (XML)	SASB/SCC20/DMC_WG/P1636.2	John Sheppard	Christy Bahn	52	manage
IEEE Std 1636.99-2013, IEEE Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA): Common Information Elements.	SASB/SCC20/DMC_WG/1636.99	Mike Seavey	Christy Bahn	47	manage
IEEE Standard for Receiver Fixture Interface	SASB/SCC20/HI_WG/1505	David Droste	Christy Bahn	48	manage
IEEE Standard for the Common Test Interface Pin Map Configuration for High-Density, Single-Tier Electronics Test Requirements Utilizing IEEE Std 1505	SASB/SCC20/HI_WG/1505.1	Stephen Mann	Christy Bahn	43	manage
IEEE Standard for the Universal Test Interface Framework and Pin Configuration for Portable/Benchtop Test Requirements Utilizing IEEE 1505(TM) Receiver Fixture Interface Standard	SASB/SCC20/HI_WG/1505.3	Stephen Mann	Christy Bahn	27	manage
Recommended Practice for the Design and Integration of Fixtures Applied to Generic Test Interfaces of Automatic Test Systems	SASB/SCC20/HI_WG/P1514	Stephen Mann	Christy Bahn	8	manage
Standard for the Common Test Interface Pin Map Configuration for High-Density, Single-Tier Electronics Test Requirements Utilizing IEEE Std 1505	SASB/SCC20/p1505.1/P1505.1	Robert Spinner	Christy Bahn	2	manage
Recommended Practice for IEEE 1671 Test Equipment Templates and Extension Classes for Describing Intrinsic Signal Path Information for Cables, Interface Adaptors and Test Equipment	SASB/SCC20/P1871.2/P1871.2	Mike Seavey	Christy Bahn	4	manage
IEEE Standard for Signal and Test Definition	SASB/SCC20/TAD_WG/1641	Chris Gorringe	Christy Bahn	60	manage

Working Group Quorum



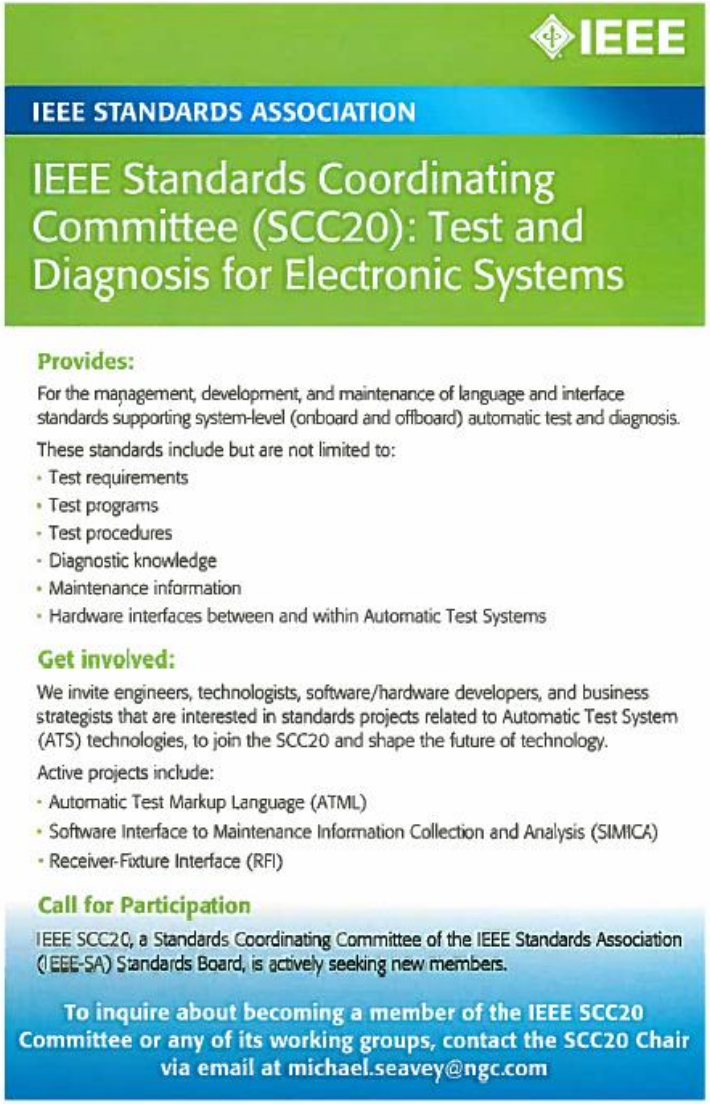
IEEE Guide for the Use of IEEE Std 1641, IEEE Standard for Signal and Test Definition	SASB/SCC20/TAD_WG/1641.1	Chris Gorringe	Christy Bahn	53	manage
Guide for the Use of IEEE Std 1641, IEEE Standard for Signal and Test Definition Amendment to add Guidelines for producing reusable Test Signal Frameworks (TSFs) for use on platforms utilizing Automatic Test Markup Language (ATML)	SASB/SCC20/TAD_WG/P1641.1a	Ion Neag	Christy Bahn	9	manage
Standard for Automatic Test Markup Language (ATML) Test Description	SASB/SCC20/TAD_WG/P1671.1	Anand Jain	Christy Bahn	60	manage
Standard for Automatic Test Markup Language (ATML) Unit Under Test (UUT) Description	SASB/SCC20/TAD_WG/P1671.3	Ion Neag	Christy Bahn	66	manage
IEEE Standard Test Language for All Systems - Common/Abbreviated Test Language for All Systems (C/ATLAS)	SASB/SCC20/TAD_WG/716	Mike Seavey	Christy Bahn	43	manage
IEEE Guide to the Use of the ATLAS Specification	SASB/SCC20/TAD_WG/771	Mike Seavey	Christy Bahn	41	manage
IEEE Standard for Automatic Test Markup Language (ATML) for Exchanging Automatic Test Equipment and Test Information via XML	SASB/SCC20/TII_WG/1671	Mike Seavey	Christy Bahn	51	manage
IEEE Standard for Automatic Test Markup Language (ATML) Instrument Description	SASB/SCC20/TII_WG/1671.2	Chris Gorringe	Christy Bahn	40	manage
IEEE Standard for Automatic Test Markup Language (ATML) Test Configuration	SASB/SCC20/TII_WG/1671.4	Mike Seavey	Christy Bahn	70	manage
IEEE Standard for Automatic Test Markup Language (ATML) Test Adapter Description	SASB/SCC20/TII_WG/1671.5	Chris Gorringe	Christy Bahn	50	manage
IEEE Standard for Automatic Test Markup Language (ATML) Test Station Description	SASB/SCC20/TII_WG/1671.6	Chris Gorringe	Christy Bahn	50	manage
IEEE Recommended Practice for Using IEEE 1671.2(TM) Instrument Description Templates for Describing Synthetic Instrumentation for Classes of Instruments such as Waveform Generators, Digitizers, External Oscillators, and Up and Down Converters	SASB/SCC20/TII_WG/1871.1	Mike Seavey	Christy Bahn	28	manage

SCC20 Activity since the 15-2 Meeting

- SCC20 Financial Report
  - Submitted in January
- SCC20 Annual Report
  - Created and Submitted to the SASB in January
    - SASB approved the report on March 3
      - ➢ Reporting IEEE Society Membership
      - ✓ P1671.1 & P1671.3 Extension #2
- New SCC20 web-page collaboration with Christy
  - Includes Working Groups/The Old Subcommittees
- Collaboration with IEC TC91 WG 15

SCC20 Activity since the 15-2 Meeting

- A SCC20 Flyer was created to promote the committee and encourage participation.
  - 5 ½ X 8 inches
  - Copies are available
- Similar Flyers for ATML, SIMICA, AI-ESTATE and RFI are in work.



IEEE

IEEE STANDARDS ASSOCIATION

IEEE Standards Coordinating Committee (SCC20): Test and Diagnosis for Electronic Systems

Provides:

For the management, development, and maintenance of language and interface standards supporting system-level (onboard and offboard) automatic test and diagnosis.

These standards include but are not limited to:

- Test requirements
- Test programs
- Test procedures
- Diagnostic knowledge
- Maintenance information
- Hardware interfaces between and within Automatic Test Systems

Get involved:

We invite engineers, technologists, software/hardware developers, and business strategists that are interested in standards projects related to Automatic Test System (ATS) technologies, to join the SCC20 and shape the future of technology.

Active projects include:

- Automatic Test Markup Language (ATML)
- Software Interface to Maintenance Information Collection and Analysis (SIMICA)
- Receiver-Fixture Interface (RFI)

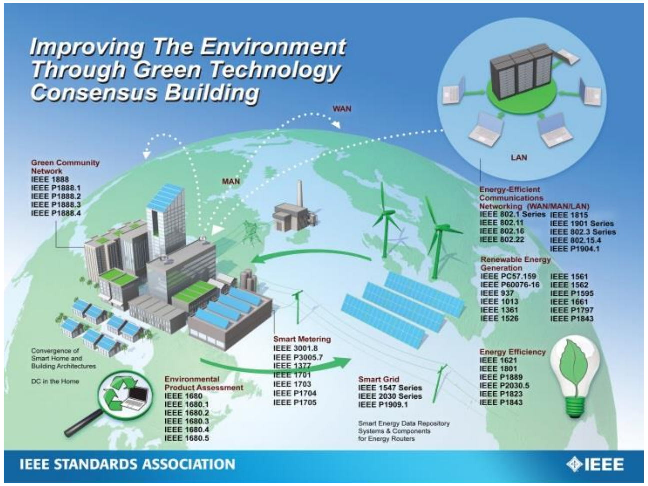
Call for Participation

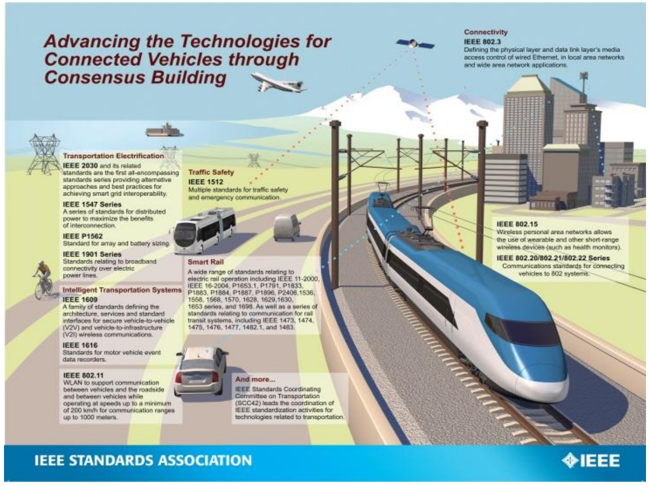
IEEE SCC20, a Standards Coordinating Committee of the IEEE Standards Association (IEEE-SA) Standards Board, is actively seeking new members.

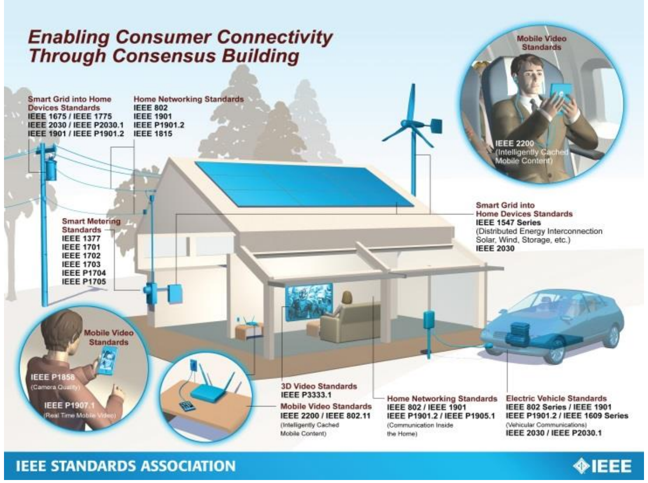
To inquire about becoming a member of the IEEE SCC20 Committee or any of its working groups, contact the SCC20 Chair via email at michael.seavey@ngc.com

SCC20 Activity since the 15-2 Meeting

- IEEE Infographics

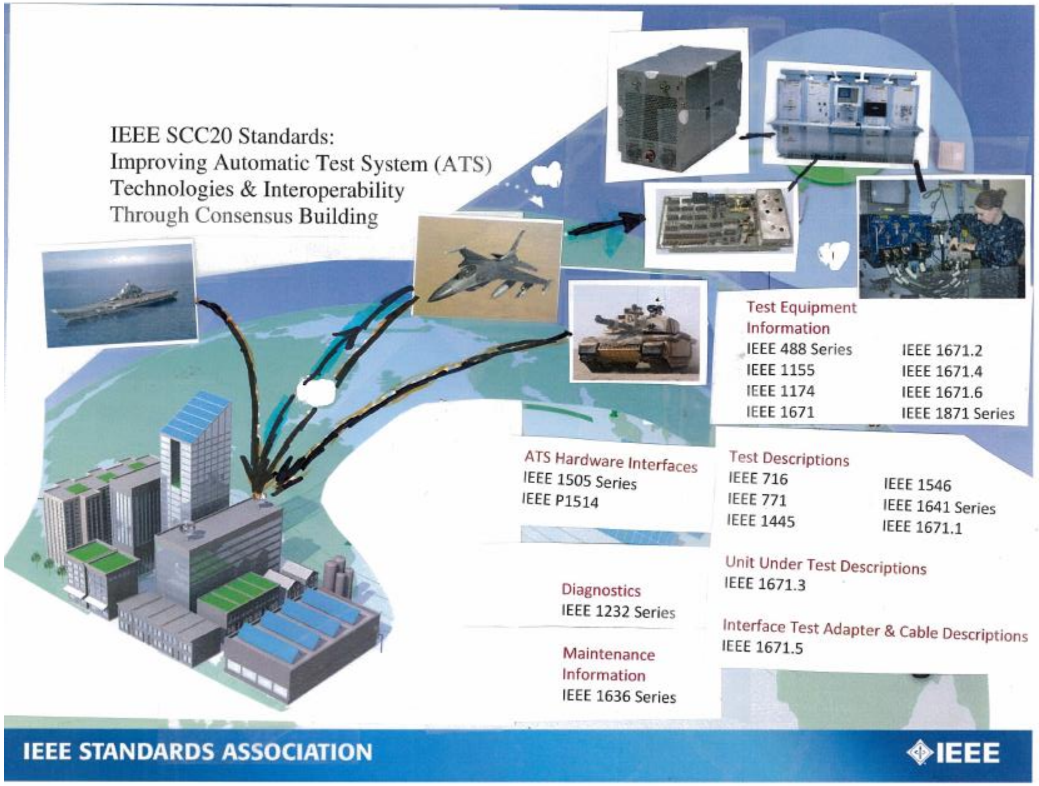






SCC20 Activity since the 15-2 Meeting

- SCC20 Infographic
  - Conceptual Drawing Developed
  - 50th Anniversary material has taken precedence.



IEEE SCC20 Standards:
Improving Automatic Test System (ATS)
Technologies & Interoperability
Through Consensus Building

Test Equipment Information
IEEE 488 Series
IEEE 1155
IEEE 1174
IEEE 1671
IEEE 1671.2
IEEE 1671.4
IEEE 1671.6
IEEE 1871 Series

ATS Hardware Interfaces
IEEE 1505 Series
IEEE P1514

Test Descriptions
IEEE 716
IEEE 771
IEEE 1445
IEEE 1546
IEEE 1641 Series
IEEE 1671.1

Unit Under Test Descriptions
IEEE 1671.3

Diagnostics
IEEE 1232 Series

Interface Test Adapter & Cable Descriptions
IEEE 1671.5

Maintenance Information
IEEE 1636 Series

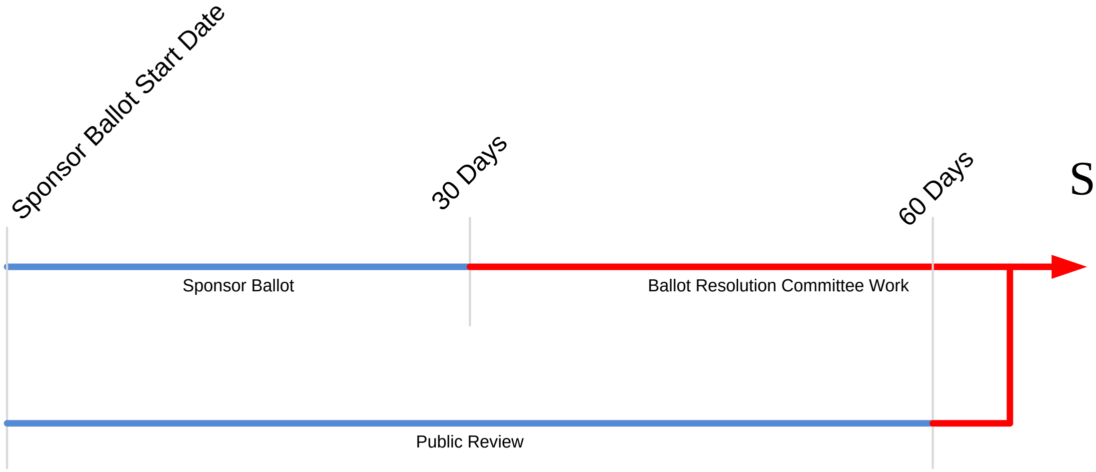
IEEE STANDARDS ASSOCIATION
IEEE

Reminders:

- PAR wording does not require "Steering" approval.
  - Is the PAR within SCC20's Scope?
  - Are resources to do the work available?

- **Initiating a Sponsor Ballot requires that the Working Group receive "Steering" approval**.
  - Majority approval vote

- Public Review of Standards in Sponsor Ballot.



Started July 6, 2015

IEEE Std 1445-1998

- A copy of IEEE 1445 in honor of Brit Frank is available for anyone to sign if you wish.

Questions ?